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Role of Urbach energy in material science

Defect states in semiconductors are one of the main focuses of all semiconductor studies. Many different approaches are used to determine the defect's origin, character and densities. One of the often overlooked semiconductor's parameters related to the defect states is the Urbach energy. It is an easily accessible measure of material disorder. Here, the process of obtaining the Urbach energy and the information which can be gained from it will be discussed.

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